Search Notes

EAST Searched (attached)

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Applicant(s)/Patent Under Reexamination

LEE ET AL.

Examiner

Korea Int'l Property Office (search for Penta Micro as assignee/applicant)

Consulted with AU 2624 SPE Brian Werner re: requirement for information

Art Unit

Barry Drennan

4133

SEARCHED

| Class | Subclass | Date | Examiner |
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| 382 | 262 | 11/03/2008 | B. Drennan |

| SEARCH NOTES | | |
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| | 10/30/2008 | B. Drennan |
| l in 2 parts) | 11/5/2008 | B. Drennan |

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